



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Yasushi KOUBUCHI, ET AL.

10-619039

Serial No.:

Rule 1.53(b) continuation of U.S. Patent Application

Serial No.: 10/075,246, filed February 15, 2002

Filed:

July 14, 2003

For:

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SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE, AND

FABRICATION PROCESS AND DESIGNING METHOD

**THEREOF** 

Group of parent:

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Examiner of parent: Lee

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## UNDER 37 CFR §1.97 AND §1.98

Mail Stop DD Commissioner for Patents P.O. Box 1450 Arlington, VA 22313-1450

July 30, 2003

Sir:

Pursuant to Applicants' duty of disclosure, enclosed please find a List of documents cited in prior application Serial No.: 10/075,246, filed February 15, 2002.

Since application Serial No. 10/075,246 is being cited under 35 U.S.C. §120 in the above-identified Continuation application, copies of the listed documents are not enclosed. See 37 CFR §1.98(d).

To the extent that the above-listed documents are not English, the requirements of 37 CFR §1.98(a)(3) are satisfied at least by the English translations enclosed with the documents as submitted in prior application. Serial No.: 10/075, 246

AUG - 1 2003 C 2800 MAIL ROOM In view of all of the foregoing, consideration of the listed documents, upon examination of the above-identified application, is respectfully requested.

Kindly charge any additional fees due, or credit overpayment of fees, to Deposit Account No. 01-2135 (501.36127CC3).

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

Ralph T. Webb

Registration No. 33,047

1300 North Seventeenth Street Suite 1800

Arlington, VA 22209 Tel.: 703-312-6600 Fax.: 703-312-6666

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30 2003 Sheet 1 of 1 6rm PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DKT. NO. SERIAL NO. PATENT AND TRADEMARK OFFICE 501.36127CC2 APPLICANT INFORMATION DISCLOSURE STATEMENT KOUBUCHI, et al. BY APPLICANT FILING DATE **GROUP** (Use several sheets if necessary)

## **U.S. PATENT DOCUMENTS**

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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
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## FOREIGN PATENT DOCUMENTS

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						Yes	No
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	Lee, et al., "An Optimized Densification of the Filled Oxide for Quarter Micron Shallow Trench Isolation (STI)", 1996, Symposium on VLSI Technology Digest of Technical Papers, pp. 158-159.
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July 10, 2003

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